LABORATARIO QUALIFICATO ◆ QUALIFIZIERTES LABOR ◆ 認可實驗室 ◆ QUALIFIED LABORATORY

ATTESTATION OF QUALIFICATION

Product Service

This is to confirm that

PV Products Testing Center of Jetion Solar (China)

No. 1011, Zhencheng Road, Shengang, Jiangyin,
Wuxi, Jiangsu, China

has been accepted as Qualified Laboratory by

TÜV SÜD Product Service

This document states that the above named company is included in the TÜV SÜD PRODUCT SERVICE Listing of Recognized Laboratories and is qualified according to the **External Laboratory Program (ELP)** for the mutually agreed product categories and/ or standards as listed in the attachment.

The testing facilities were assessed to meet the relevant requirements of this program as **T**esting at **M**anufactures **P**remises (TMP). Test results from testing conducted at this laboratory under the supervision and witness of engineer(s) of TÜV SÜD can be used as a basis for a TÜV SÜD certification.

Expiration Date: 2023-10-25

On behalf of TÜV SÜD Product Service GmbH

Zhang Zhulin
Solar / Photovoltaic's (PV) Quality Manager

TÜV SÜD Product Service GmbH
Date of Issuance: 2022-10-26

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Annex - Scope of CTF Jetion (valid until 2023-10-25)

Category	Standard	Details (see note below)
PV	IEC 61215:2016	MQT01 Visual inspection MQT02 Maximum power determination MQT03 Insulation test MQT04 Measurement of temperature coefficients MQT10 UV preconditioning test MQT11 Thermal cycling test MQT12 Humidity-freeze test MQT13 Damp heat test MQT15 Wet leakage current test MQT16 Static mechanical load test MQT17 Hail test MQT18 Bypass diode thermal test MQT19 Stabilization
PV	IEC 61730-2 :2016	MST01 Visual inspection MST02 Performance at STC MST03 Maximum power determination MST11 Accessibility test MST12 Cut susceptibility test MST13 Continuity test of equipotential bonding MST16 Insulation test MST17 Wet leakage current test MST34 Mechanical load test MST51 Thermal cycling test MST52 Humidity-freeze test MST53 Damp-heat test MST54 UV test
PV	IEC TS 62804-1: 2015	Photovoltaic (PV) modules – Test methods for the detection of potential-induced degradation – Part 1: Crystalline silicon